N-channel TrenchMOS intermediate level FET Rev. 3 — 14 October 2010

Product data sheet

Product profile 1.

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

Table 1 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

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Parameter	Conditions		Min	Тур	Max	Unit
drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	40	V
drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	A
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	204	W
aracteristics						
drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>		-	3.05	3.6	mΩ
	Parameter drain-source voltage drain current total power dissipation tracteristics drain-source on-state	$\begin{array}{ll} \text{drain-source} & T_j \geq 25 \ ^{\circ}\text{C}; \ T_j \leq 175 \ ^{\circ}\text{C} \\ \text{voltage} & \text{drain current} & \text{V}_{\text{GS}} = 10 \ \text{V}; \ T_{\text{mb}} = 25 \ ^{\circ}\text{C}; \\ \text{see} \ \overline{\text{Figure 1}} & \text{total power} \\ \text{dissipation} & \text{T}_{\text{mb}} = 25 \ ^{\circ}\text{C}; \ \text{see} \ \overline{\text{Figure 2}} \\ \text{drain-source} & \text{V}_{\text{GS}} = 10 \ \text{V}; \ \text{I}_{\text{D}} = 25 \ \text{A}; \\ \text{on-state} & \text{T}_{\text{j}} = 25 \ ^{\circ}\text{C}; \ \text{see} \ \overline{\text{Figure 11}} \\ \end{array}$	ParameterConditionsdrain-source voltage $T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$ drain current $V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 2total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 2tracteristics $V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ on-statedrain-source on-state $V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ T _j = 25 °C; see Figure 11	ParameterConditionsMindrain-source voltage $T_j \ge 25 \ ^{\circ}C; \ T_j \le 175 \ ^{\circ}C$ -drain current $V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C;$ [1]-total power dissipation $T_{mb} = 25 \ ^{\circ}C;$ see Figure 2-total power dissipation $T_{mb} = 25 \ ^{\circ}C;$ see Figure 2-tracteristics $V_{GS} = 10 \ V; \ I_D = 25 \ A;$ on-state-	ParameterConditionsMinTypdrain-source voltage $T_j \ge 25 \ ^\circ\text{C}; \ T_j \le 175 \ ^\circ\text{C}$ drain current $V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^\circ\text{C};$ [1]total power dissipation $T_{mb} = 25 \ ^\circ\text{C};$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\text{C};$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\text{C};$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\text{C};$ see Figure 1	ParameterConditionsMinTypMaxdrain-source voltage $T_j \ge 25 ^\circ\text{C}; T_j \le 175 ^\circ\text{C}$ 40drain current $V_{GS} = 10 ^\circ\text{V}; T_{mb} = 25 ^\circ\text{C};$ [1]100total power dissipation $T_{mb} = 25 ^\circ\text{C};$ see Figure 2204tracteristicsdrain-source on-state $V_{GS} = 10 ^\circ\text{V}; I_D = 25 ^\circ\text{C};$ -3.053.6



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Table 1.	Quick reference da	tacontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 100 \text{ A}; V_{sup} \leq 40 \text{V}; \\ R_{GS} &= 50 \Omega; V_{GS} = 10 \text{V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	368	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure } 13}{\text{Figure } 14};$ $\text{see } \frac{\text{Figure } 14}{\text{Figure } 14}$	-	42	-	nC

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
2	D	Drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT226 (I2PAK)	

3. Ordering information

Table 3. Ordering	g information		
Type number	Package		
	Name	Description	Version
BUK6E3R4-40C	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Мах	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	40	V
V _{GS}	gate-source voltage	Pulsed	<u>[1]</u>	-20	20	V
		DC	[2]	-16	16	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{10000000000000000000000000000000000$	[3]	-	100	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 1	[3]	-	100	А
I _{DM}	peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed};$ see Figure 3		-	657	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	204	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drai	n diode					
I _S	source current	T _{mb} = 25 °C	[3]	-	100	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	657	А
Avalanche r	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$\label{eq:ld} \begin{array}{l} I_{D} = 100 \; A; \; V_{sup} \leq 40 \; V; \; R_{GS} = 50 \; \Omega; \\ V_{GS} = 10 \; V; \; T_{j(init)} = 25 \; ^{\circ}C; \; unclamped \end{array}$		-	368	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		<u>[4][5][6]</u>	-	-	J

[1] Accumulated pulse duration not to exceed 5mins.

[2] -16V accumulated duration not to exceed 168 hrs.

[3] Continuous current is limited by package.

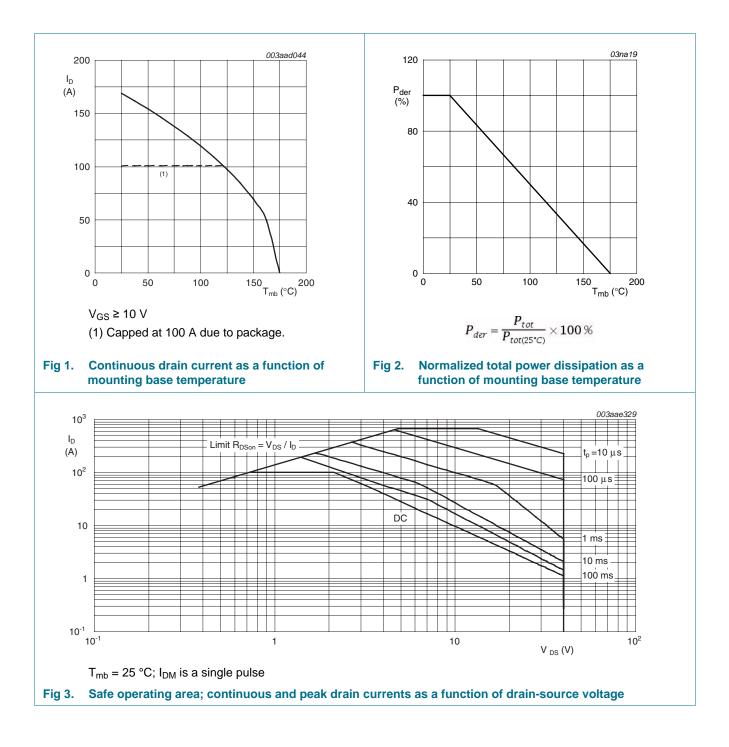
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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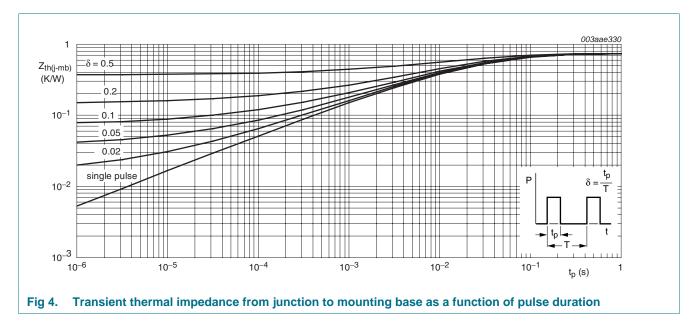
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5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	0.74	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W



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6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$	40	-	-	V
	breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 10</u>	-	-	3.3	V
		I_D = 2.5 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 10</u>	0.8	-	-	V
DSS	drain leakage current	V _{DS} = 40 V; V _{GS} = 0 V; T _j = 175 °C	-	-	500	μA
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = 20 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
		V _{DS} = 0 V; V _{GS} = -20 V; T _j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	3.05	3.6	mΩ
		V _{GS} = 5 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	4.2	5.3	mΩ
		V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 11</u>	-	4.5	6	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	7.6	mΩ
Dynamic	characteristics					
Q _{G(tot)} total gate ch	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	125	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	71	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	23	-	nC
Q _{GD}	gate-drain charge	see Figure 13; see Figure 14	-	42	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	6016	8020	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	739	870	pF
C _{rss}	reverse transfer capacitance		-	510	700	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	40	-	ns
r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	87	-	ns
d(off)	turn-off delay time		-	224	-	ns
-(,	fall time		-	117	-	ns
L _D	internal drain inductance	from drain lead 6 mm from package to centre of die; T _j = 25 °C	-	4.5	-	nH
L _S	internal source inductance	from source lead to source bond pad; $T_i = 25 ^{\circ}\text{C}$	-	7.5	-	nH

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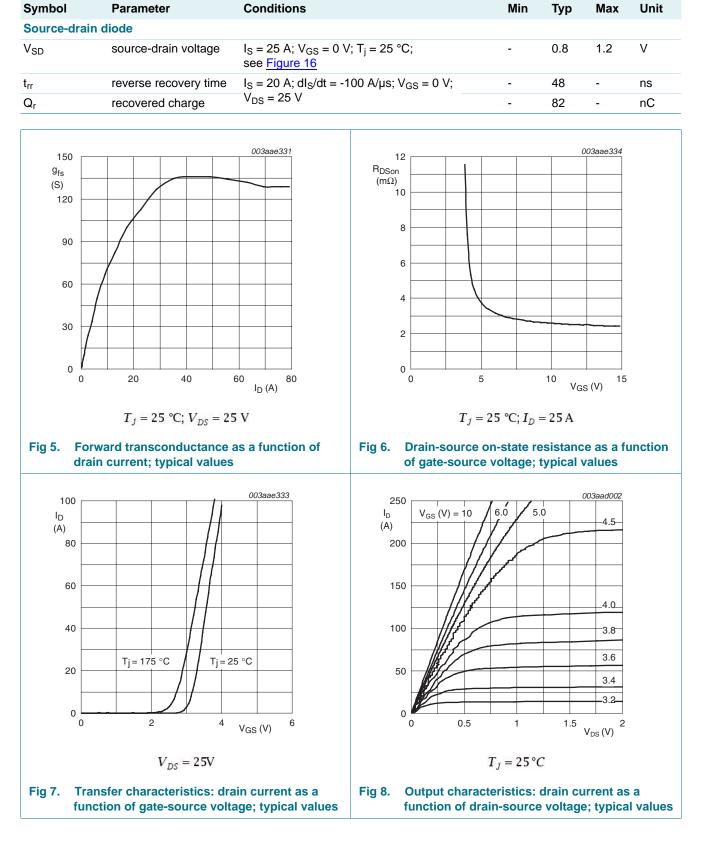
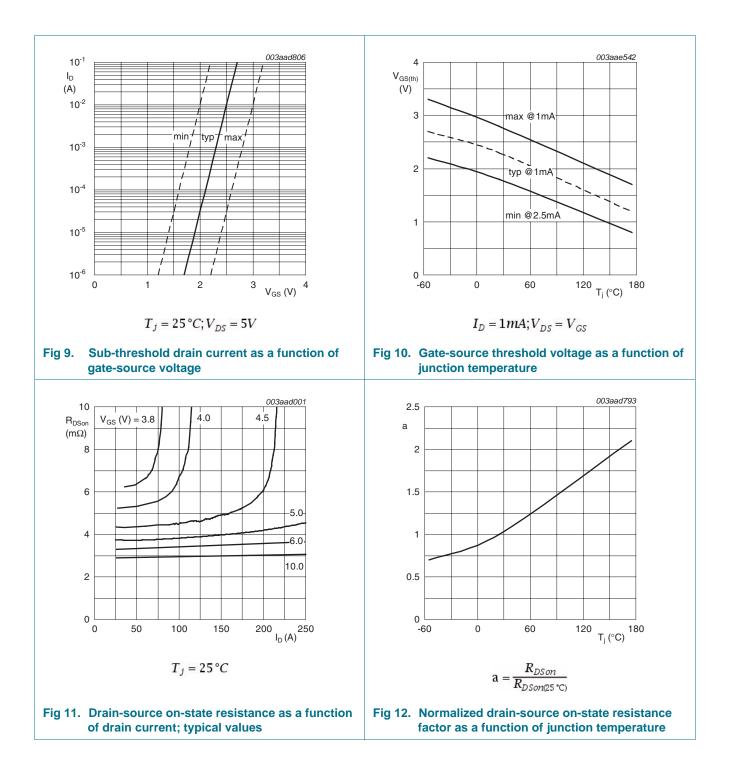


Table 6. Characteristics ...continued

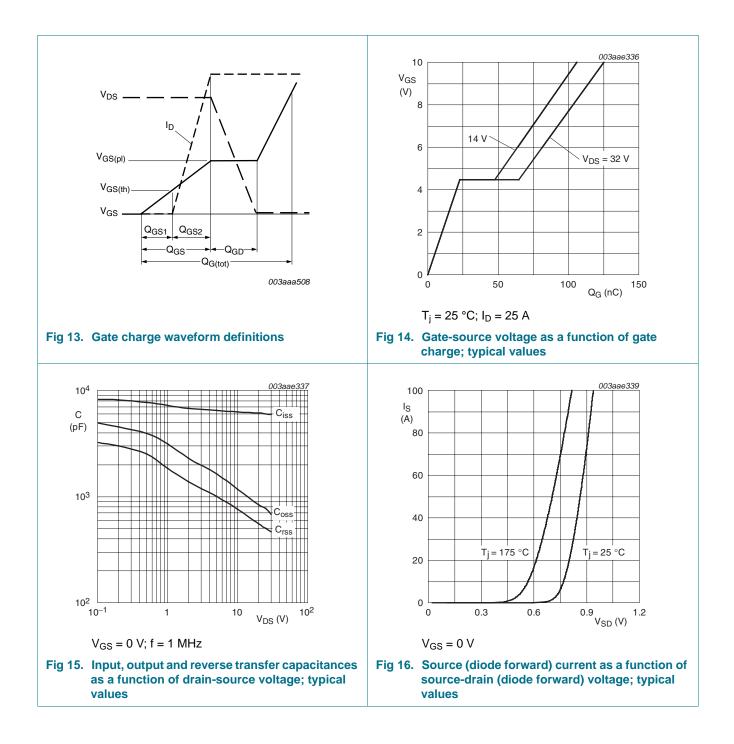
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7. Package outline

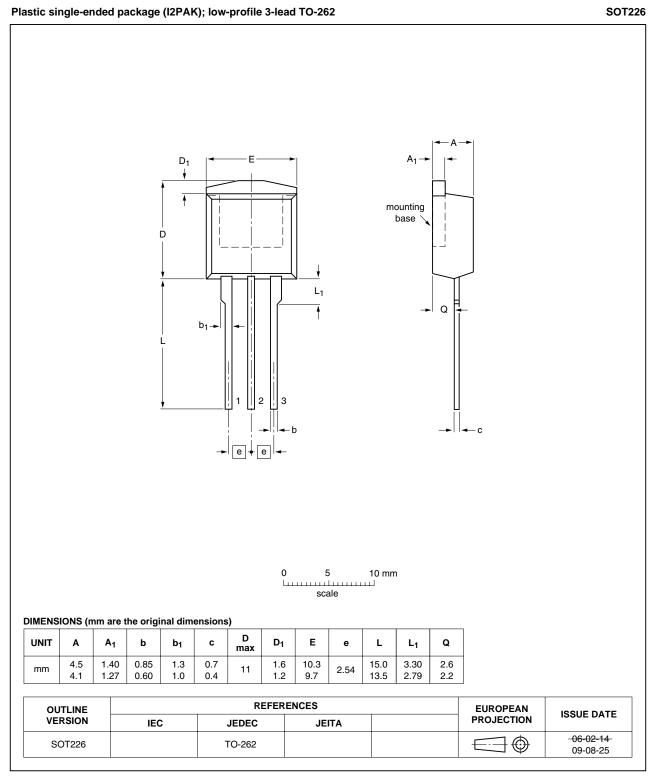


Fig 17. Package outline SOT226 (I2PAK)

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8. Revision history

Table 7.Revision h	nistory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK6E3R4-40C v.3	20101014	Product data sheet	-	BUK6E3R4-40C v.2
Modifications:	 Status change 	d from objective to product.		
BUK6E3R4-40C v.2	20100621	Objective data sheet	-	BUK6E3R4-40C v.1

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Legal information 9.

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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